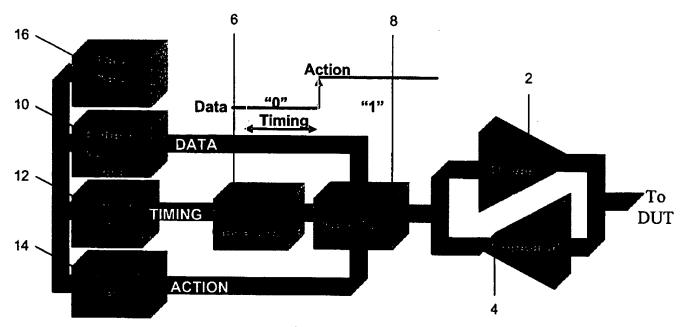
Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR

INTEGRATED CIRCUITS Appln. No: Not Yet Assigned Filed: Concurrently Herewith
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Action = Pattern Data \* Timing Data (Limited by TimeSet) \* Waveset \* Drive

Figure 1

Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR

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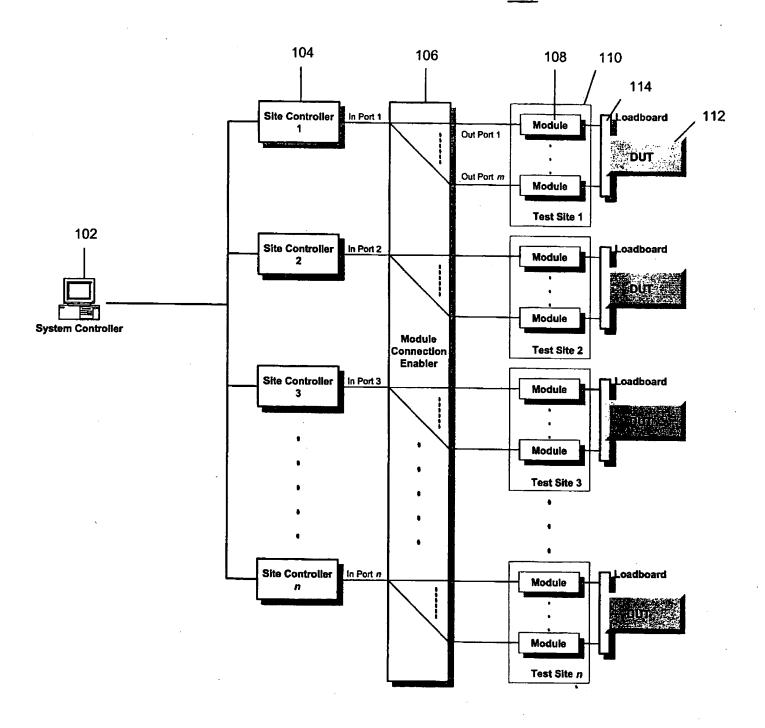


Figure 2

Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR INTEGRATED CIRCUITS

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200 -

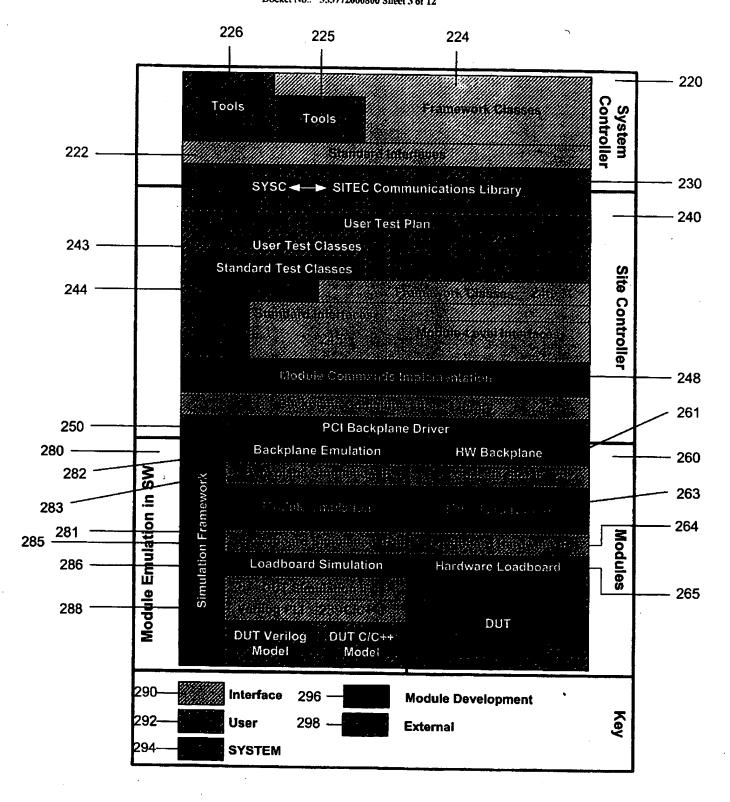


Figure 3

Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR INTEGRATED CIRCUITS

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<u>400</u>

**TPL** Compiler

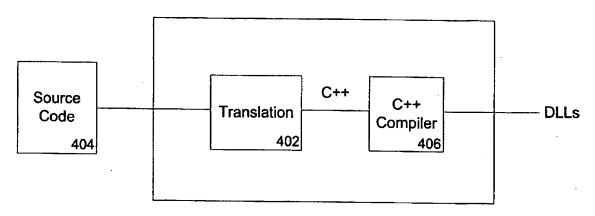


Figure 4

Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR INTEGRATED CIRCUITS
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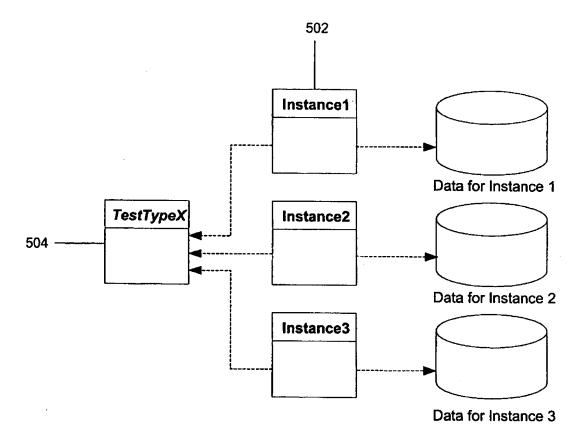
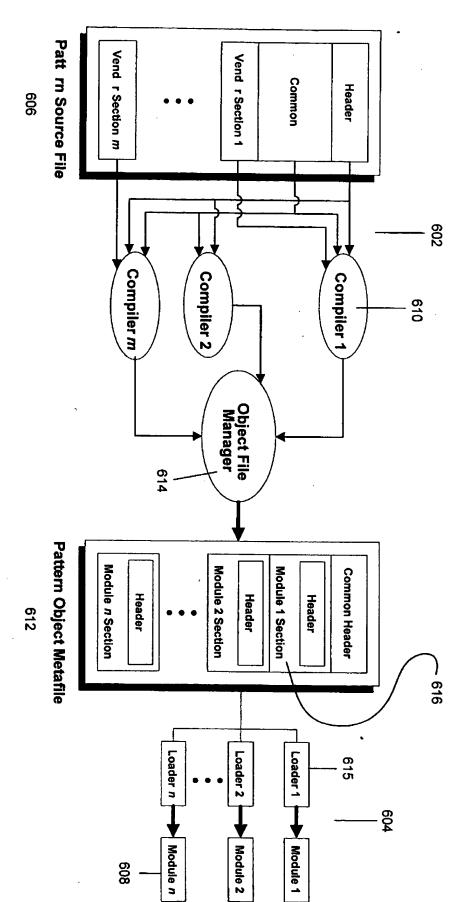


Figure 5

Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR

Figure 6

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Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR INTEGRATED CIRCUITS Appln. No: Not Yet Assigned Filed: Concurrently Herewith Docket No.: 333772000800 Sheet 7 of 12

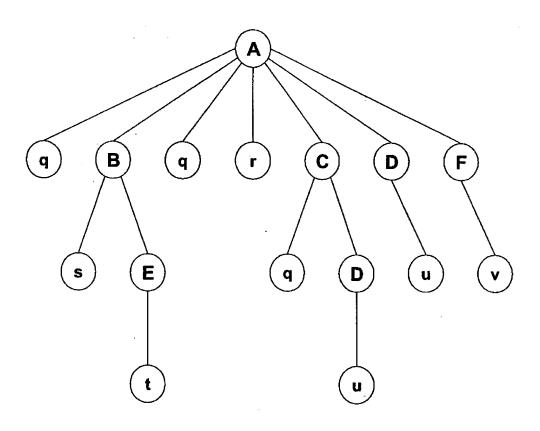


Figure 7

Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR INTEGRATED CIRCUITS Appln. No: Not Yet Assigned Filed: Concurrently Herewith Docket No.: 333772000800 Sheet 8 of 12

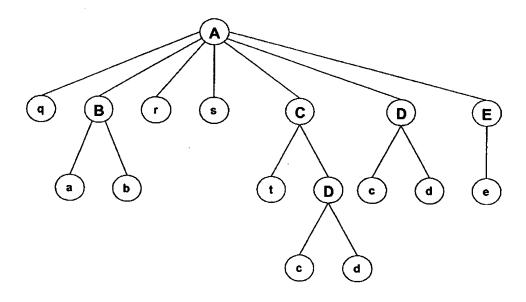


Figure 8

Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR INTEGRATED CIRCUITS

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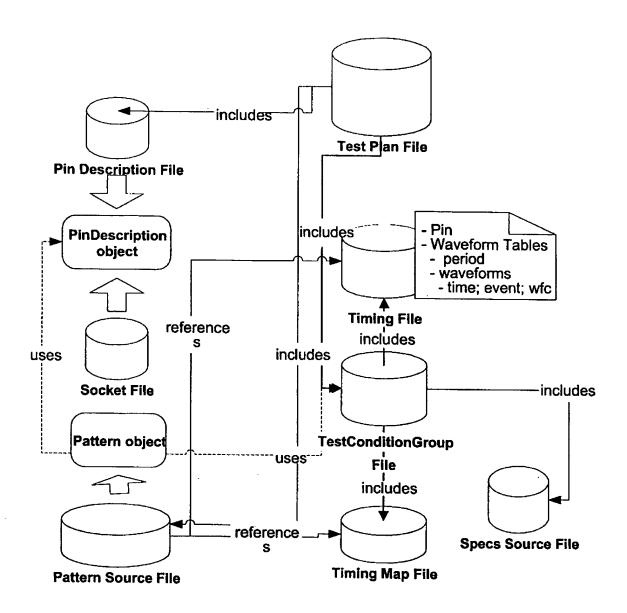


Figure 9

Title: METHOD AND STRUCTURE TO DEVELOP
A TEST PROGRAM FOR SEMICONDUCTOR

INTEGRATED CIRCUITS
Appln. No: Not Yet Assigned
Filed: Concurrently Herewith

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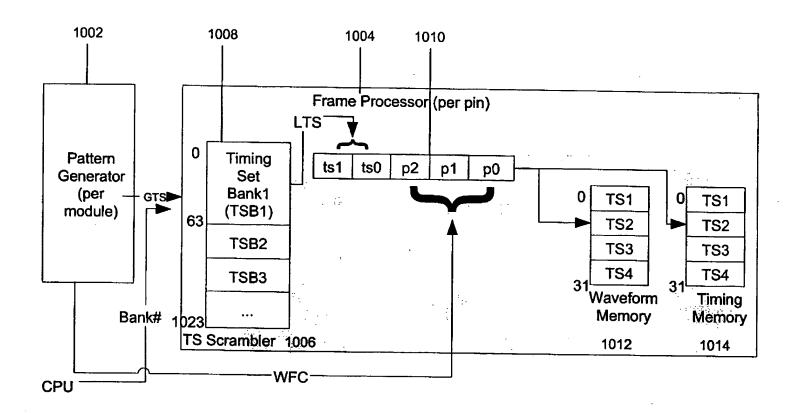


Figure 10

Tille: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR INTEGRATED CIRCUITS

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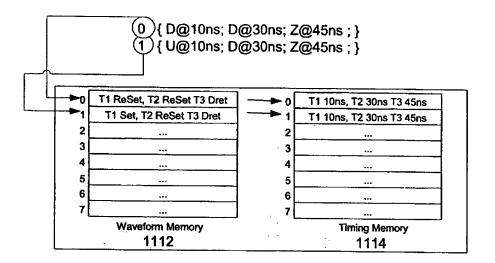


Figure 11

Title: METHOD AND STRUCTURE TO DEVELOP A TEST PROGRAM FOR SEMICONDUCTOR

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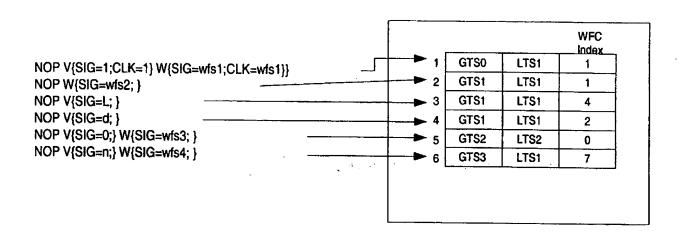


Figure 12